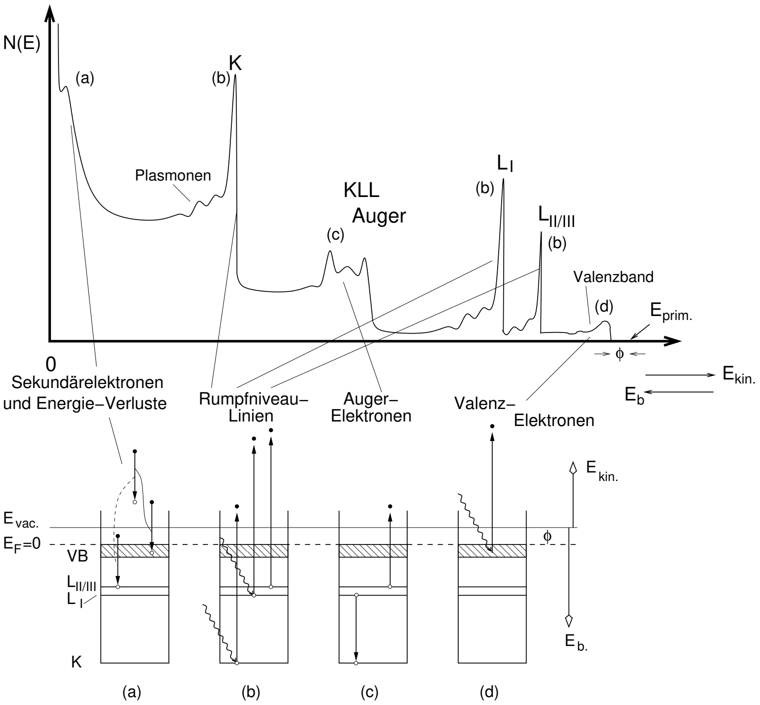
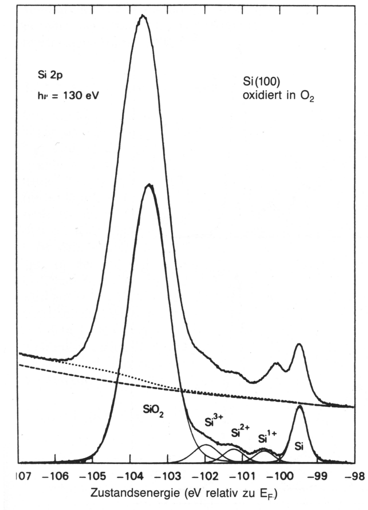
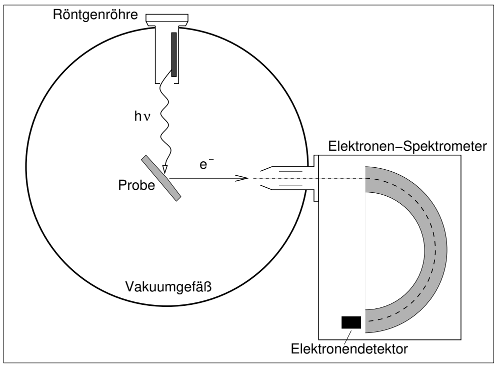
2.2.1. Rumpfniveau-Spektroskopie I: XPS



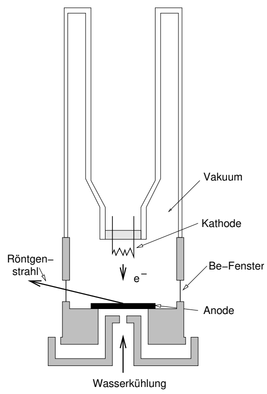
Typisches XPS-Spektrum mit Elementarprozesssen



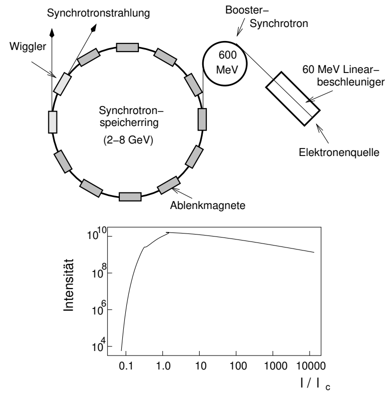
XPS-Spektrum von oxidiertem Si(100) nahe des Si 2p-Niveuas (Synchrotron, 130 eV)



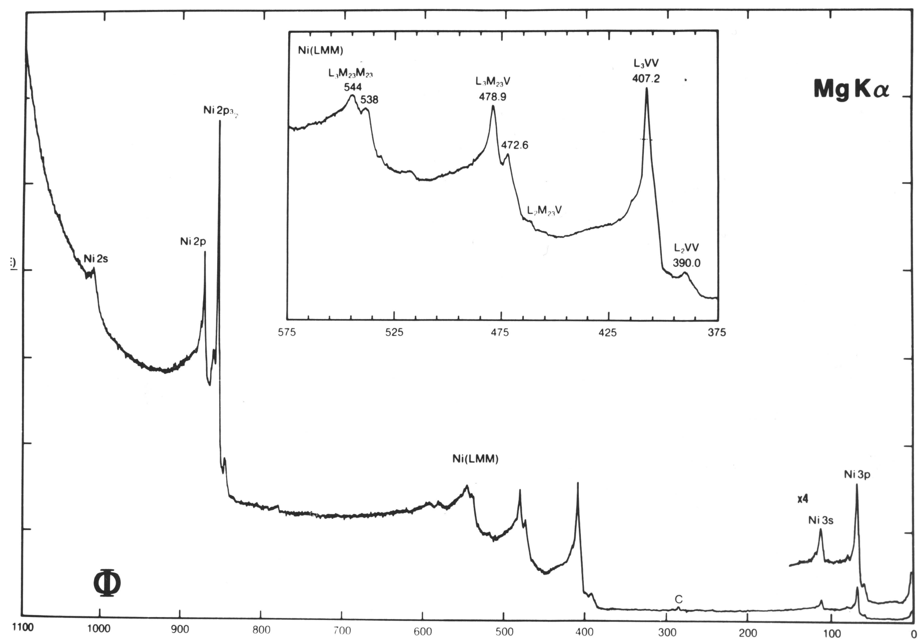
Prinzipaufbau einer XPS-Anlage



Röntgenröhre



Synchotron



XPS-Spektrum von elementarem Ni